

## Notice of References Cited

Application/Control No. 10/039,333

LEE Art U

Applicant(s)/Patent Under Reexamination LEE ET AL.

Art Unit

1765

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

Examiner

Binh X Tran

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,551,942	04-2003	Naeem	438/714
	В	US-6,136,211	10-2000	Qian et al.	216/37
	С	US-5,164,330	11-1992	Davis et al.	438/654
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.